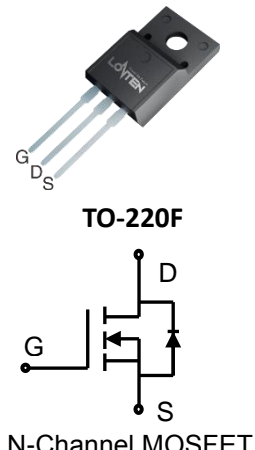


Lonten N-channel 500V, 16A Power MOSFET

<p>Description</p> <p>The Power MOSFET is fabricated using the advanced planar VDMOS technology. The resulting device has low conduction resistance, superior switching performance and high avalanche energy.</p> <p>Features</p> <ul style="list-style-type: none"> ● Low $R_{DS(on)}$ ● Low gate charge (typ. $Q_g = 51.9nC$) ● 100% UIS tested ● RoHS compliant <p>Applications</p> <ul style="list-style-type: none"> ● Power factor correction. ● Switched mode power supplies. ● LED driver. 	<p>Product Summary</p> <table style="width: 100%; border: none;"> <tr><td style="padding: 2px;">V_{DSS}</td><td style="padding: 2px;">500V</td></tr> <tr><td style="padding: 2px;">I_D</td><td style="padding: 2px;">16A</td></tr> <tr><td style="padding: 2px;">$R_{DS(on),max}$</td><td style="padding: 2px;">0.36Ω</td></tr> <tr><td style="padding: 2px;">$Q_{g,typ}$</td><td style="padding: 2px;">51.9nC</td></tr> </table> <p>Pin Configuration</p> <div style="text-align: center;">  <p>TO-220F</p> <p>N-Channel MOSFET</p> </div>	V_{DSS}	500V	I_D	16A	$R_{DS(on),max}$	0.36 Ω	$Q_{g,typ}$	51.9nC
V_{DSS}	500V								
I_D	16A								
$R_{DS(on),max}$	0.36 Ω								
$Q_{g,typ}$	51.9nC								

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	500	V
Continuous drain current ¹⁾		($T_C = 25^\circ C$)	16
		($T_C = 100^\circ C$)	11
Pulsed drain current ²⁾	I_{DM}	48	A
Gate-Source voltage	V_{GSS}	± 30	V
Avalanche energy, single pulse ³⁾	E_{AS}	1037	mJ
Power Dissipation	P_D	37	W
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ C$
Continuous diode forward current	I_S	16	A
Diode pulse current	$I_{S,pulse}$	48	A

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	3.4	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient ⁴⁾	$R_{\theta JA}$	62	$^\circ C/W$
Soldering temperature, wave soldering only allowed at leads. (1.6mm from case for 10s)	T_{sold}	260	$^\circ C$

Package Marking and Ordering Information

Device	Device Package	Marking	Units/Tube
LND16N50	TO-220F	LND16N50	50

Electrical Characteristics
 $T_c = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV_{DSS}	$V_{GS}=0V, I_D=0.25mA$	500	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=0.25mA$	2.0	-	4.0	V
Drain cut-off current	I_{DSS}	$V_{DS}=500V, V_{GS}=0V, T_j = 25^\circ\text{C}$	-	-	1	μA
Gate leakage current, Forward	I_{GSSF}	$V_{GS}=30V, V_{DS}=0V$	-	-	100	nA
Gate leakage current, Reverse	I_{GSSR}	$V_{GS}=-30V, V_{DS}=0V$	-	-	-100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=8A$ $T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$	-	0.26 0.65	0.36	Ω
Dynamic characteristics						
Input capacitance	C_{iss}	$V_{DS} = 25V, V_{GS} = 0V,$ $f = 250kHz$	-	2680	-	pF
Output capacitance	C_{oss}		-	246	-	
Reverse transfer capacitance	C_{rss}		-	13.6	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 250V, I_D = 16A$ $R_G = 10\Omega, V_{GS}=10V$	-	76.6	-	ns
Rise time	t_r		-	9.6	-	
Turn-off delay time	$t_{d(off)}$		-	57.7	-	
Fall time	t_f		-	11.2	-	
Gate charge characteristics						
Gate to source charge	Q_{gs}	$V_{DD}=400V, I_D=16A$ $V_{GS}=0$ to $10V$	-	10.3	-	nC
Gate to drain charge	Q_{gd}		-	16.9	-	
Gate charge total	Q_g		-	51.9	-	
Gate plateau voltage	$V_{plateau}$		-	4.5	-	V
Reverse diode characteristics						
Diode forward voltage	V_{SD}	$V_{GS}=0V, I_F=16A$	-	-	1.3	V
Reverse recovery time	t_{rr}	$V_R=400V, I_F=16A,$ $di_F/dt=100A/\mu s$	-	351	-	ns
Reverse recovery charge	Q_{rr}		-	3991	-	μC
Peak reverse recovery current	I_{rrm}		-	17.6	-	A

Notes:

1. Drain current limited by maximum junction temperature, TO-220 equivalent.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. $I_{AS}=14.4A, L=10mH, V_{DD}=60V, \text{Starting } T_j=25^\circ\text{C}.$
4. The value of R_{thJA} is measured by placing the device in a still air box which is one cubic foot.

Electrical Characteristics Diagrams

Figure 1. Typ. Output Characteristics

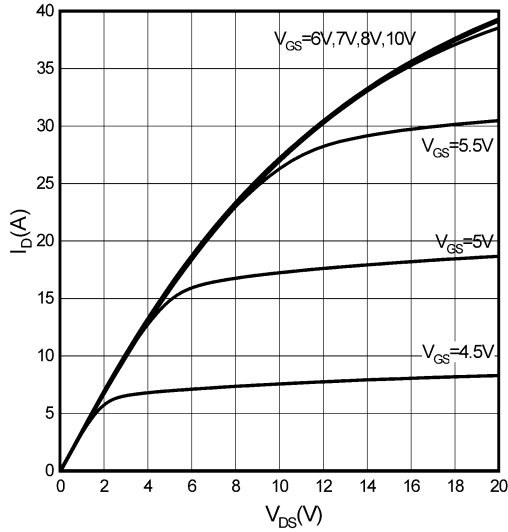


Figure 2. Transfer Characteristics

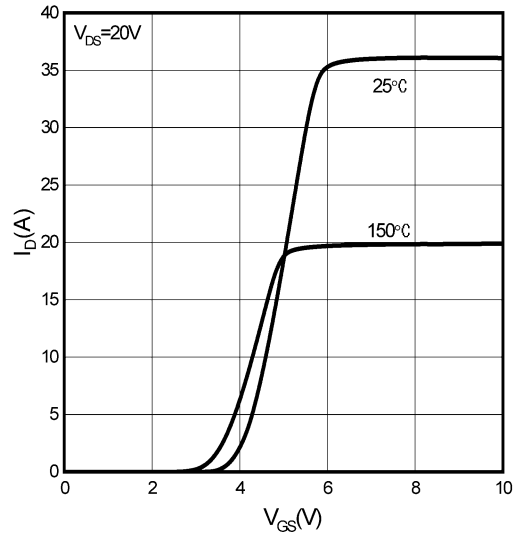


Figure 3. On-Resistance vs. Drain Current

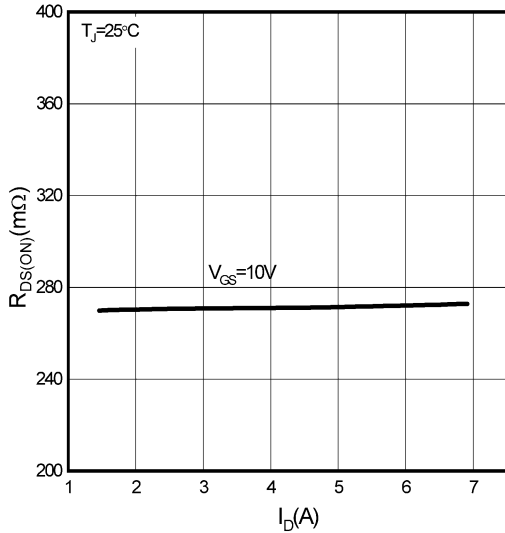


Figure 4. On-Resistance vs. Temperature

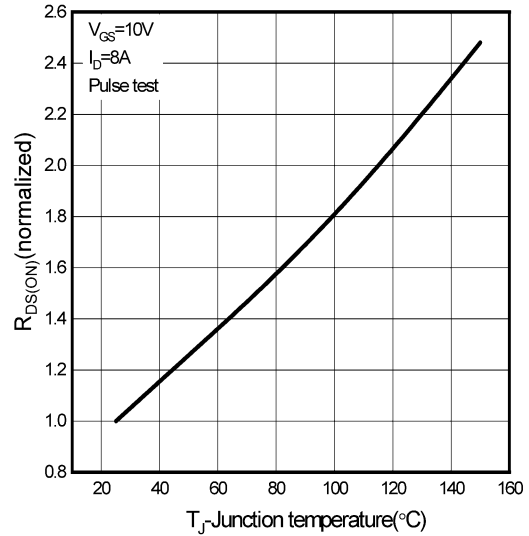


Figure 5. Breakdown Voltage vs. Temperature

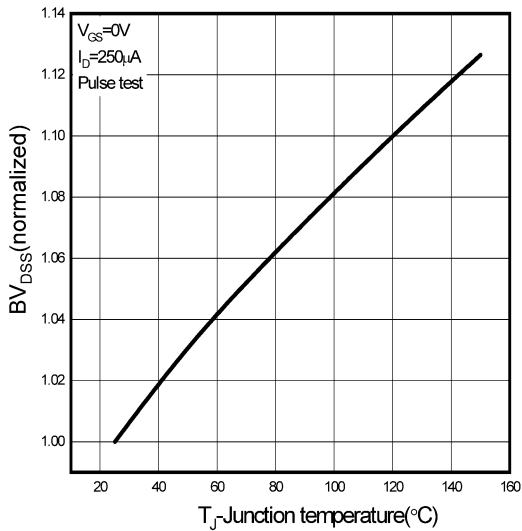


Figure 6. Threshold Voltage vs. Temperature

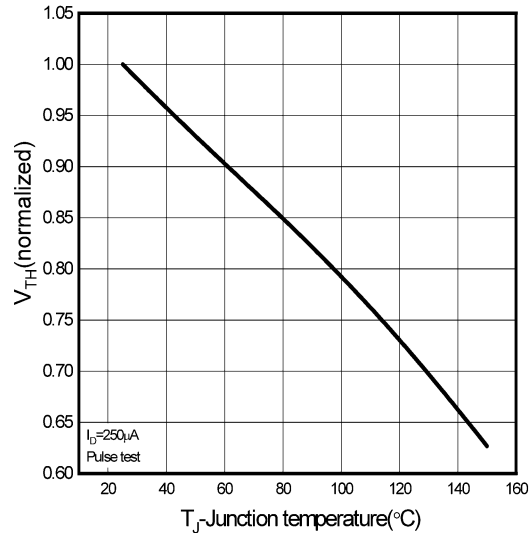


Figure 7. $R_{DS(on)}$ vs. Gate Voltage

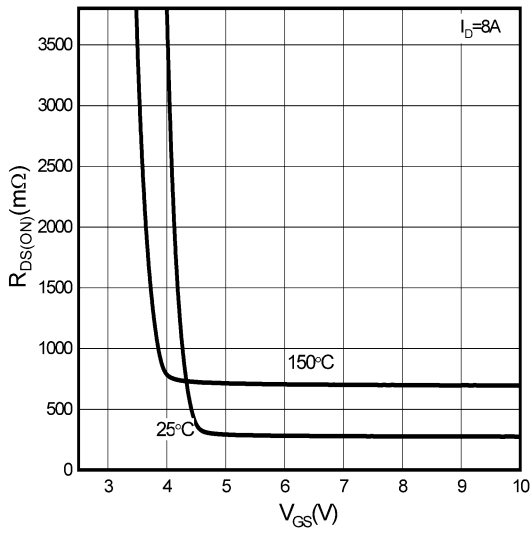


Figure 8. Body-Diode Characteristics

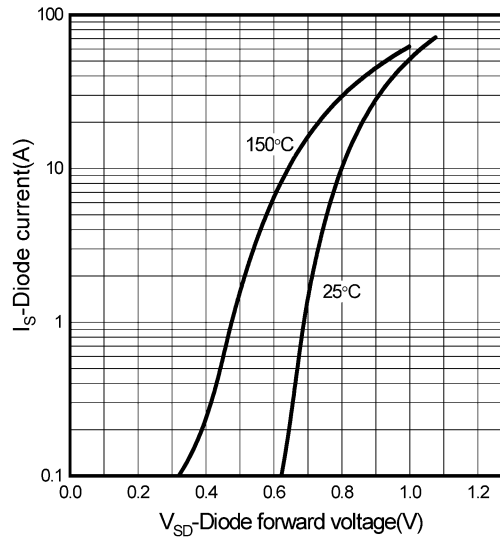


Figure 9. Capacitance Characteristics

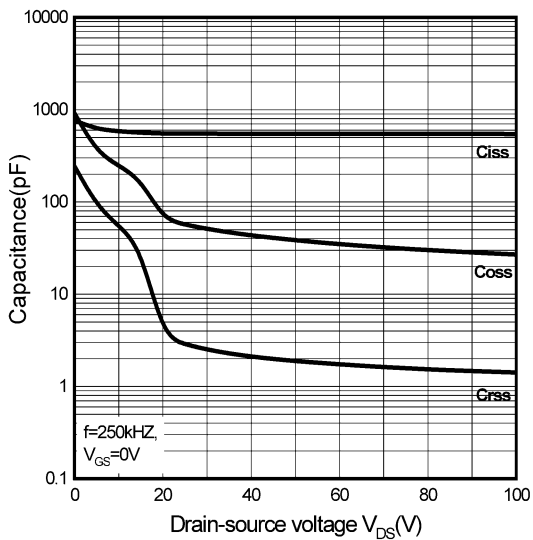


Figure 10. Gate Charge Characteristics

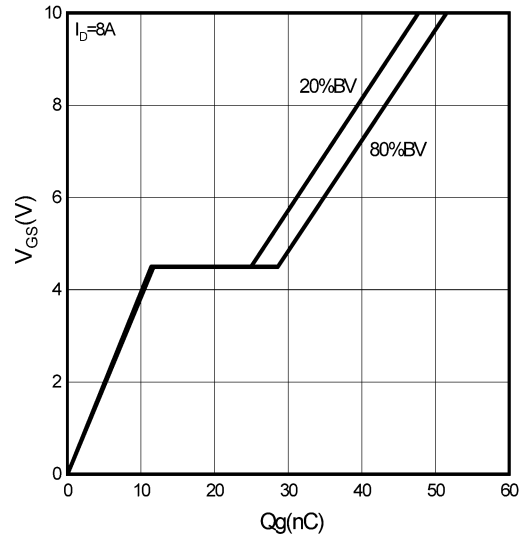


Figure 11. Drain Current Derating

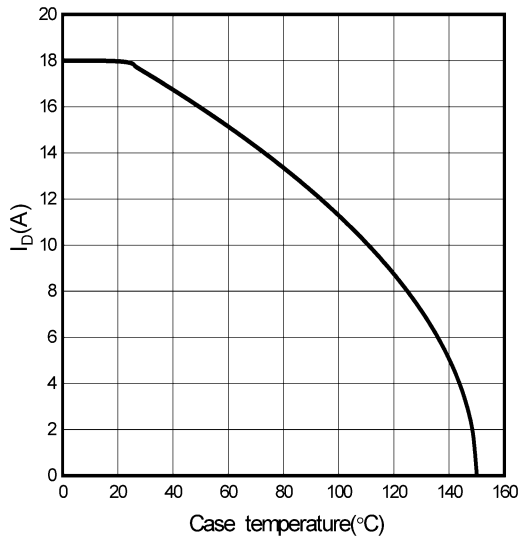


Figure 12. Power Dissipation vs. Temperature

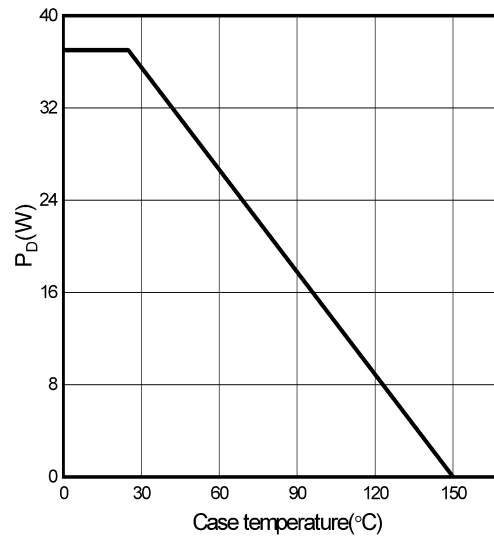


Figure 13. Safe Operating Area

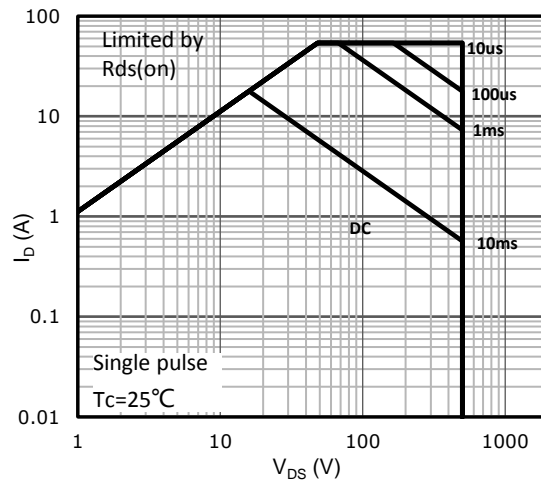
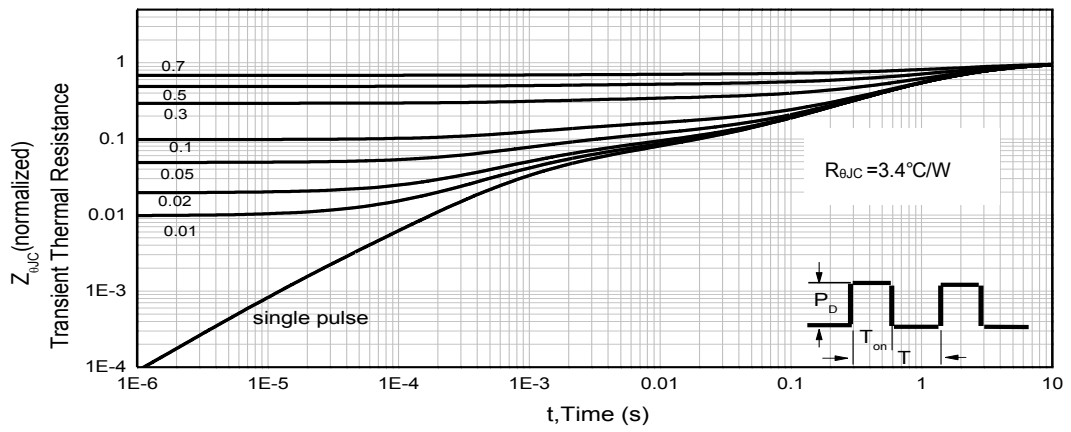
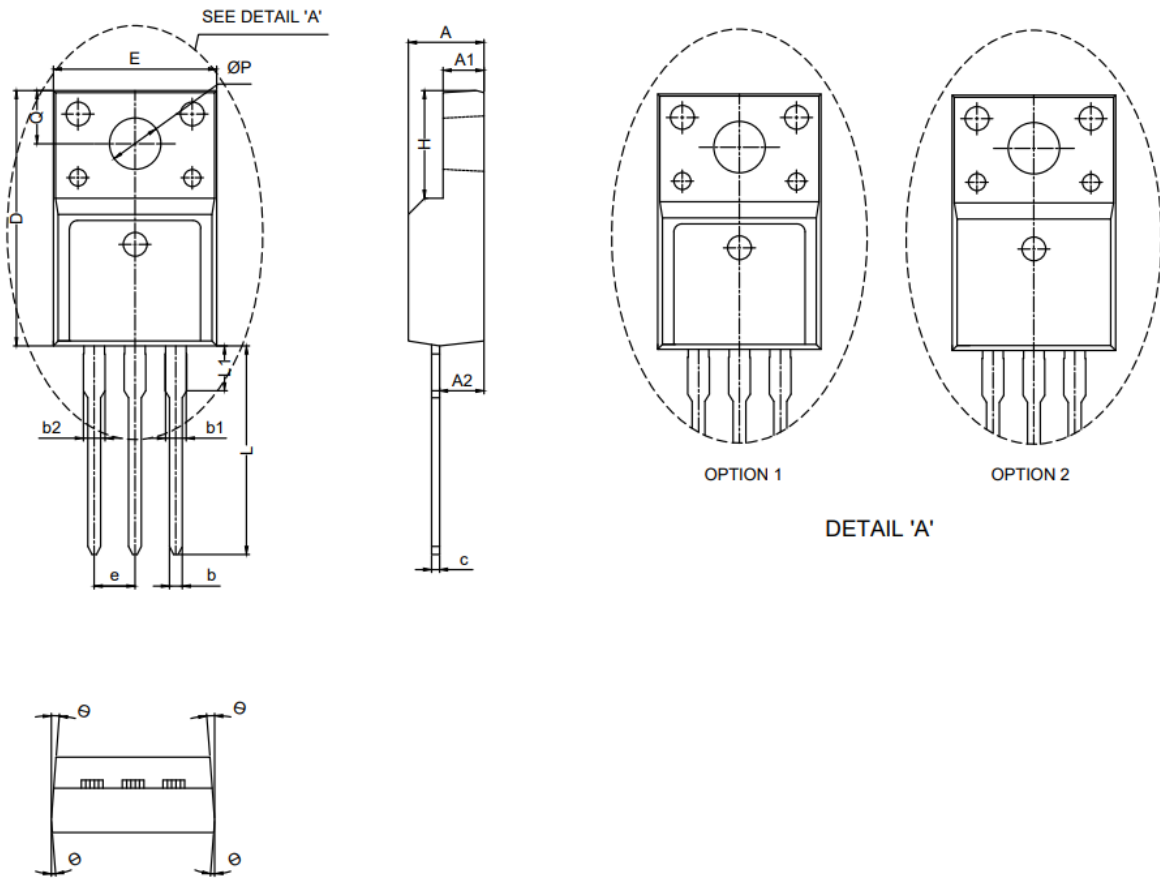


Figure 14. Normalized Maximum Transient Thermal Impedance (R_{thJC})



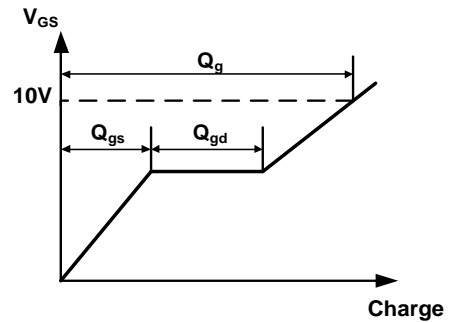
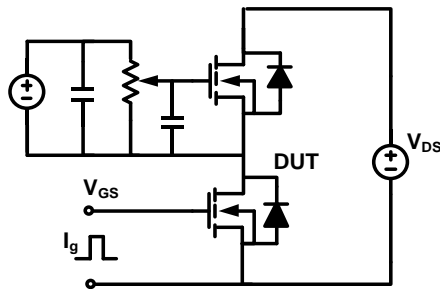
Mechanical Dimensions for TO-220F



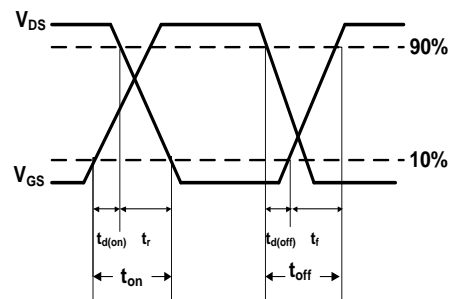
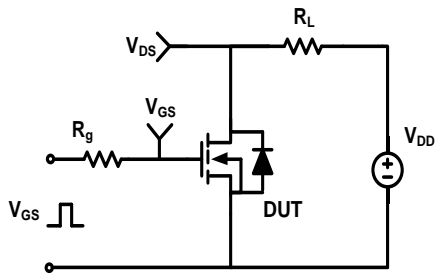
SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.40	4.90	0.173	0.193
A1	2.34	2.74	0.092	0.108
A2	2.50	2.96	0.098	0.117
b	0.70	1.00	0.028	0.039
b1	1.18	1.43	0.046	0.056
b2	1.15	1.58	0.045	0.062
c	0.40	0.70	0.016	0.028
D	15.57	16.40	0.613	0.646
E	9.96	10.40	0.392	0.409
e	2.54 BSC		0.100 BSC	
H	6.48	7.25	0.255	0.285
L	12.64	14.20	0.498	0.559
L1	2.90	3.60	0.114	0.142
ØP	3.00	3.38	0.118	0.133
Q	3.10	3.50	0.122	0.138
Ø	1°	5°	1°	5°

Test Circuit & Waveforms

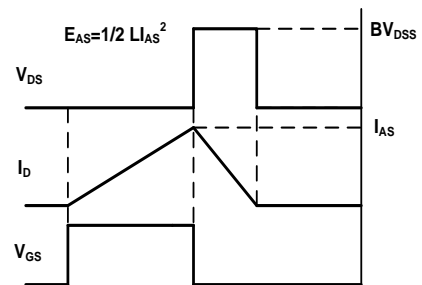
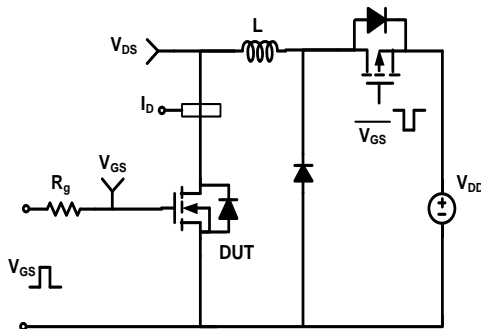
Gate Charge Test Circuit & Waveform



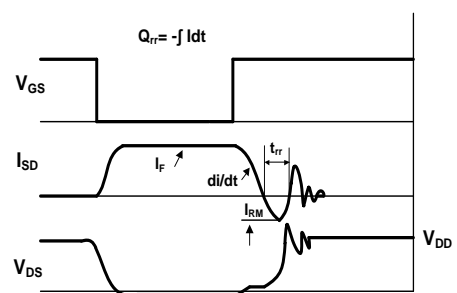
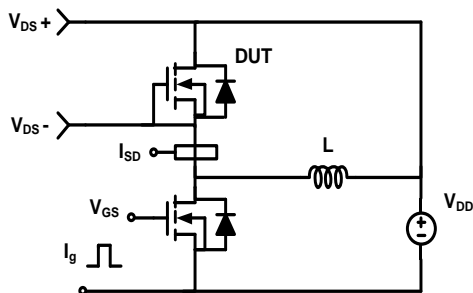
Resistive Switching Test Circuit & Waveform



Unclamped Inductive Switching (UIS) Test Circuit & Waveform



Diode Recovery Test Circuit & Waveform



Version Information

LND16N50

Revision 1.0

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